

# **IGBT3** Chip

#### Features:

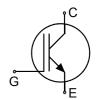
- 650V Trench & Field Stop technology
- low V<sub>CE(sat)</sub>
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling
- Qualified according to JEDEC for target applications

## **Recommended for:**

power modules

# **Applications:**

• drives



Chip Type	V <sub>CE</sub>	<b>/</b> Cn <sup>1)</sup>	Die Size	Package
SIGC39T65E	650V	75A	6.59 x 5.91 mm <sup>2</sup>	sawn on foil

<sup>1)</sup> nominal collector current at Tc = 100°C, not subject to production test - verified by design/characterization

## **Mechanical Parameters**

Mechanical I aramet				
Die size		6.59 x 5.91		
Emitter pad size (incl. gate pad)		See chip drawing		
Gate pad size		1.52 x 0.817		
Area total		38.9		
Thickness		70	μm	
Wafer size	200	mm		
Max.possible chips pe	er wafer	686		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag –system		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		AI, <500µm		
Reject ink dot size		Ø 0.65mm ; max 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 2 < 6 month		
	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen of Humidity <25%RH, Temperature 17°C – 25°C, <		



## **Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, <i>T</i> <sub>vj</sub> =25 °C	V <sub>CE</sub>	650	V
DC collector current, limited by $T_{vj max}$	I <sub>C</sub>	1)	Α
Pulsed collector current, $t_p$ limited by $T_{vj max}^{2}$	I <sub>c,puls</sub>	225	А
Gate emitter voltage	V <sub>GE</sub>	±20	V
Operating junction temperature	T <sub>vj</sub>	-40 +175	°C
Short circuit data <sup>2</sup> ) <sup>3)</sup> $V_{GE}$ = 15V, $V_{CC}$ = 360V, $T_{vj}$ = 150°C	t <sub>sc</sub>	6	μs

<sup>1)</sup> depending on thermal properties of assembly

<sup>2</sup>) not subject to production test - verified by design/characterization

<sup>3)</sup> allowed number of short circuits: <1000; time between short circuits: >1s.

# Static Characteristics (tested on wafer), $T_{vj}$ =25 °C

Parameter	Symbol	Conditions	Value			Unit
	Cymbol		min.	typ.	max.	
Collector-Emitter breakdown voltage	V <sub>(BR)CES</sub>	V <sub>GE</sub> =0V , <i>I</i> <sub>C</sub> =4 mA	650			
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =75A	0.93	1.45	1.77	V
Gate-Emitter threshold voltage	V <sub>GE(th)</sub>	$I_{\rm C}$ =1.2mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.1	5.8	6.4	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =650V , V <sub>GE</sub> =0V			3.8	μA
Gate-Emitter leakage current	I <sub>GES</sub>	V <sub>CE</sub> =0V , V <sub>GE</sub> =20V			600	nA
Integrated gate resistor	r <sub>G</sub>			none		Ω

## Electrical Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			Unit
Falameter	Symbol		min.	typ.	max.	
Collector Emitter acturation voltage	V	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =75A,		10		V
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	<i>T</i> <sub>vj</sub> =175 °C		1.9		V
Input capacitance	Cies	V <sub>CE</sub> =25V,		4620		
		V <sub>GE</sub> =0V, <i>f</i> =1MHz				pF
Reverse transfer capacitance	C <sub>res</sub>	$T_{\rm vj}$ =25 °C		137		



# SIGC39T65E

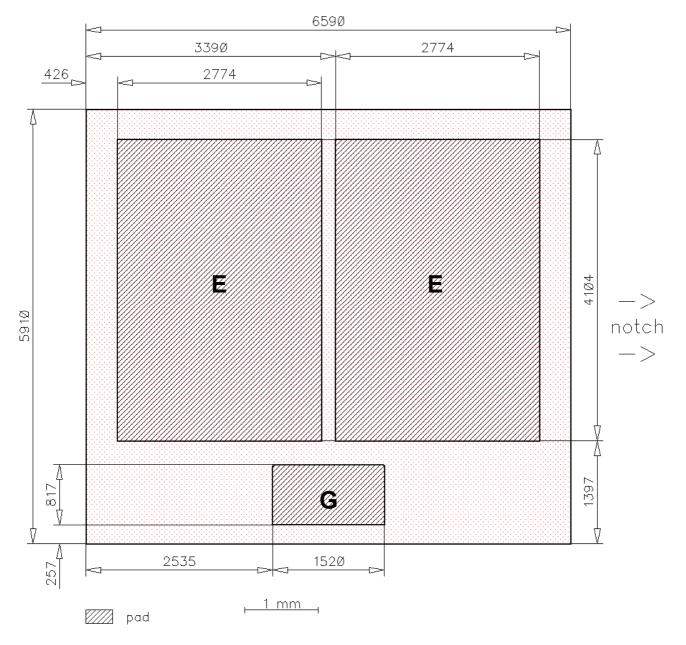
## **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	IGW75N60T	Rev 2.5
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# Chip Drawing



Die-Size 6590 um x 5910 um



G = Gate



#### Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Version	Subjects (major changes since last revision)	Date

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